



SEMICONDUCTOR®

# FSBM30SM60A SPM™ (Smart Power Module)

## **General Description**

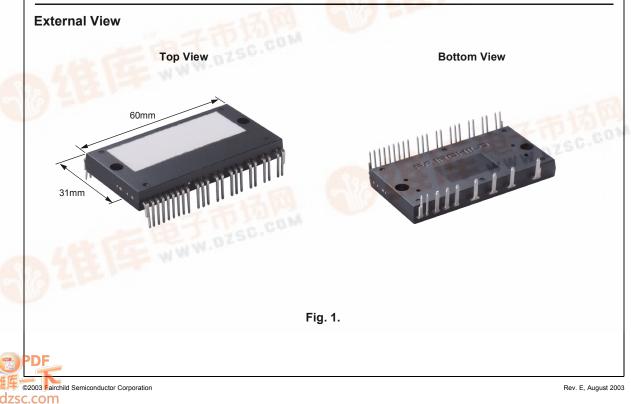
FSBM30SM60A is an advanced smart power module (SPM) that Fairchild has newly developed and designed to provide very compact and high performance ac motor drives mainly targeting medium speed low-power inverterdriven application like air conditioners. It combines optimized circuit protection and drive matched to low-loss IGBTs. Highly effective short-circuit current detection/ protection is realized through the use of advanced current sensing IGBT chips that allow continuous monitoring of the IGBTs current. System reliability is further enhanced by the integrated under-voltage lock-out protection. The high speed built-in HVIC provides opto-coupler-less IGBT gate driving capability that further reduce the overall size of the inverter system design. In addition the incorporated HVIC facilitates the use of single-supply drive topology enabling the FSBM30SM60A to be driven by only one drive supply voltage without negative bias. Inverter current sensing application can be achieved due to the divided negative dc terminals.

## Features

- UL Certified No. E209204
- 600V-30A 3-phase IGBT inverter bridge including control ICs for gate driving and protection
- Divided negative dc-link terminals for inverter current sensing applications
- Single-grounded power supply due to built-in HVIC
- Typical switching frequency of 5kHz
- Inverter power rating of 2.4kW / 100~253 Vac
- Isolation rating of 2500Vrms/min.
- Very low leakage current due to using ceramic substrate
  Adjustable current protection level by varying series
- resistor value with sense-IGBTs

## Applications

- AC 100V ~ 253V 3-phase inverter drive for small power (2.4kW) ac motor drives
- Home appliances applications requiring medium switching frequency operation like air conditioners drive system
- Application ratings:
  - Power : 2.4kW / 100~253 Vac
  - Switching frequency : Typical 5kHz (PWM Control)
- 100% load current : 11A (Irms)
- 150% load current : 16.5A (Irms) for 1 minute



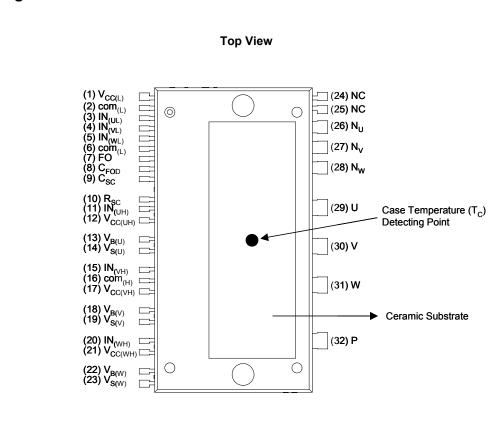
## **Integrated Power Functions**

• 600V-30A IGBT inverter for 3-phase DC/AC power conversion (Please refer to Fig. 3)

## Integrated Drive, Protection and System Control Functions

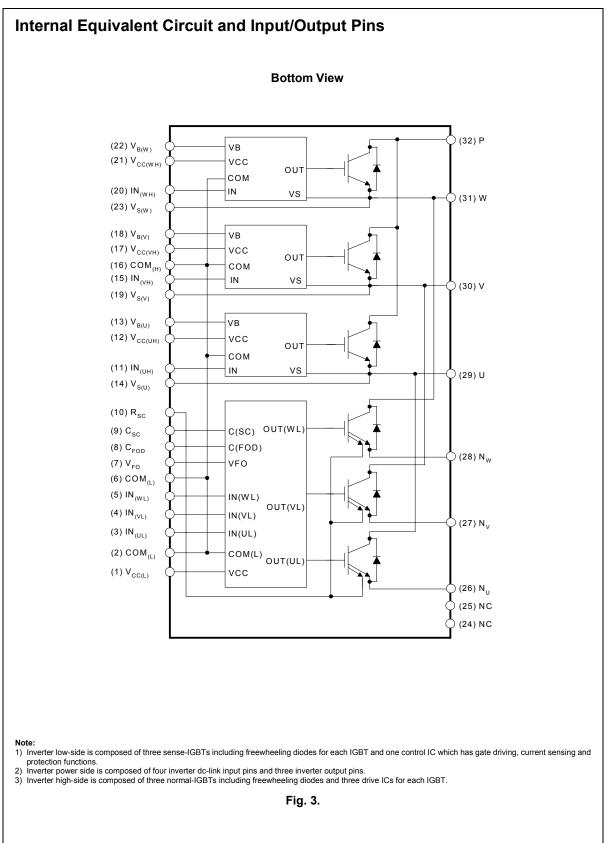
- For inverter high-side IGBTs: Gate drive circuit, High voltage isolated high-speed level shifting
   Control circuit under-voltage (UV) protection
  - Note) Available bootstrap circuit example is given in Figs. 13 and 14.
- For inverter low-side IGBTs: Gate drive circuit, Short-Circuit (SC) protection
  - Control supply circuit under-voltage (UV) protection
- Fault signaling: Corresponding to a SC fault (Low-side IGBTs) or a UV fault (Low-side control supply circuit)
- Input interface: 5V CMOS/LSTTL compatible, Schmitt trigger input

## **Pin Configuration**





Pin Number	Pin Name	Pin Description
1	V <sub>CC(L)</sub>	Low-side Common Bias Voltage for IC and IGBTs Driving
2	COM <sub>(L)</sub>	Low-side Common Supply Ground
3	IN <sub>(UL)</sub>	Signal Input for Low-side U Phase
4	IN <sub>(VL)</sub>	Signal Input for Low-side V Phase
5	IN <sub>(WL)</sub>	Signal Input for Low-side W Phase
6	COM <sub>(L)</sub>	Low-side Common Supply Ground
7	V <sub>FO</sub>	Fault Output
8	C <sub>FOD</sub>	Capacitor for Fault Output Duration Time Selection
9	C <sub>SC</sub>	Capacitor (Low-pass Filter) for Short-Circuit Current Detection Input
10	R <sub>SC</sub>	Resistor for Short-Circuit Current Detection
11	IN <sub>(UH)</sub>	Signal Input for High-side U Phase
12	V <sub>CC(UH)</sub>	High-side Bias Voltage for U Phase IC
13	V <sub>B(U)</sub>	High-side Bias Voltage for U Phase IGBT Driving
14	V <sub>S(U)</sub>	High-side Bias Voltage Ground for U Phase IGBT Driving
15	IN <sub>(VH)</sub>	Signal Input for High-side V Phase
16	COM <sub>(H)</sub>	High-side Common Supply Ground
17	V <sub>CC(VH)</sub>	High-side Bias Voltage for V Phase IC
18	V <sub>B(V)</sub>	High-side Bias Voltage for V Phase IGBT Driving
19	V <sub>S(V)</sub>	High-side Bias Voltage Ground for V Phase IGBT Driving
20	IN <sub>(WH)</sub>	Signal Input for High-side W Phase
21	V <sub>CC(WH)</sub>	High-side Bias Voltage for W Phase IC
22	V <sub>B(W)</sub>	High-side Bias Voltage for W Phase IGBT Driving
23	V <sub>S(W)</sub>	High-side Bias Voltage Ground for W Phase IGBT Driving
24	NC	No Connection
25	NC	No Connection
26	NU	Negative DC–Link Input for U Phase
27	N <sub>V</sub>	Negative DC–Link Input for V Phase
28	N <sub>W</sub>	Negative DC–Link Input for W Phase
29	U	Output for U Phase
30	V	Output for V Phase
31	W	Output for W Phase
32	Р	Positive DC-Link Input



# Absolute Maximum Ratings (T<sub>J</sub> = 25°C, Unless Otherwise Specified)

## **Inverter Part**

ltem	Symbol	Condition	Rating	Unit
Supply Voltage	V <sub>PN</sub>	Applied between P- NU, NV, NW	450	V
Supply Voltage (Surge)	V <sub>PN(Surge)</sub>	Applied between P- NU, NV, NW	500	V
Collector-Emitter Voltage	V <sub>CES</sub>		600	V
Each IGBT Collector Current	± I <sub>C</sub>	$T_{\rm C} = 25^{\circ}{\rm C}$	30	A
Each IGBT Collector Current	± I <sub>C</sub>	$T_{\rm C}$ = 100°C	16	A
Each IGBT Collector Current (Peak)	± I <sub>CP</sub>	T <sub>C</sub> = 25°C, Instantaneous Value (Pulse)	60	A
Collector Dissipation	P <sub>C</sub>	T <sub>C</sub> = 25°C per One Chip	62	W
Operating Junction Temperature	TJ	(Note 1)	-20 ~ 125	°C

Note: 1. It would be recommended that the average junction temperature should be limited to  $T_J \le 125^{\circ}C$  (@ $T_C \le 100^{\circ}C$ ) in order to guarantee safe operation.

## **Control Part**

Item	Symbol	Condition	Rating	Unit
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$ , $V_{CC(L)}$ - $COM_{(L)}$	20	V
High-side Control Bias Voltage	V <sub>BS</sub>	Applied between $V_{B(U)}$ - $V_{S(U)}$ , $V_{B(V)}$ - $V_{S(V)}$ , $V_{B(W)}$ - $V_{S(W)}$	20	V
Input Signal Voltage	V <sub>IN</sub>	$ \begin{array}{l} \mbox{Applied between IN}_{(UH)}, \mbox{IN}_{(VH)}, \mbox{IN}_{(WH)} - \mbox{COM}_{(H)} \\ \mbox{IN}_{(UL)}, \mbox{IN}_{(VL)}, \mbox{IN}_{(WL)} - \mbox{COM}_{(L)} \end{array} $	-0.3 ~ V <sub>CC</sub> +0.3	V
Fault Output Supply Voltage	V <sub>FO</sub>	Applied between V <sub>FO</sub> - COM <sub>(L)</sub>	$-0.3 \sim V_{CC} + 0.3$	V
Fault Output Current	I <sub>FO</sub>	Sink Current at V <sub>FO</sub> Pin	5	mA
Current Sensing Input Voltage	V <sub>SC</sub>	Applied between C <sub>SC</sub> - COM <sub>(L)</sub>	-0.3 ~ V <sub>CC</sub> +0.3	V

## **Total System**

Item	Symbol	Condition	Rating	Unit
Self Protection Supply Voltage Limit (Short-Circuit Protection Capability)	V <sub>PN(PROT)</sub>	$V_{CC} = V_{BS} = 13.5 \sim 16.5V$ T <sub>J</sub> = 25°C, Non-repetitive, less than 6µs	400	V
Module Case Operation Temperature	Т <sub>С</sub>	Note Fig.2	-20 ~ 100	°C
Storage Temperature	T <sub>STG</sub>		-20 ~ 125	°C
Isolation Voltage	V <sub>ISO</sub>	60Hz, Sinusoidal, AC 1 minute, Connection Pins to Heat-sink Plate	2500	V <sub>rms</sub>

# **Absolute Maximum Ratings**

## **Thermal Resistance**

ltem	Symbol	Condition	Min.	Тур.	Max.	Unit
Junction to Case Thermal Resistance	R <sub>th(j-c)Q</sub>	Each IGBT under Inverter Operating Condition	-	-	2.0	°C/W
	R <sub>th(j-c)F</sub>	Each FWDi under Inverter Operating Condition	-	-	3.2	°C/W
Contact Thermal Resistance	R <sub>th(c-f)</sub>	Ceramic Substrate (per 1 Module) Thermal Grease Applied (Note 3)	-	-	0.06	°C/W

Note:

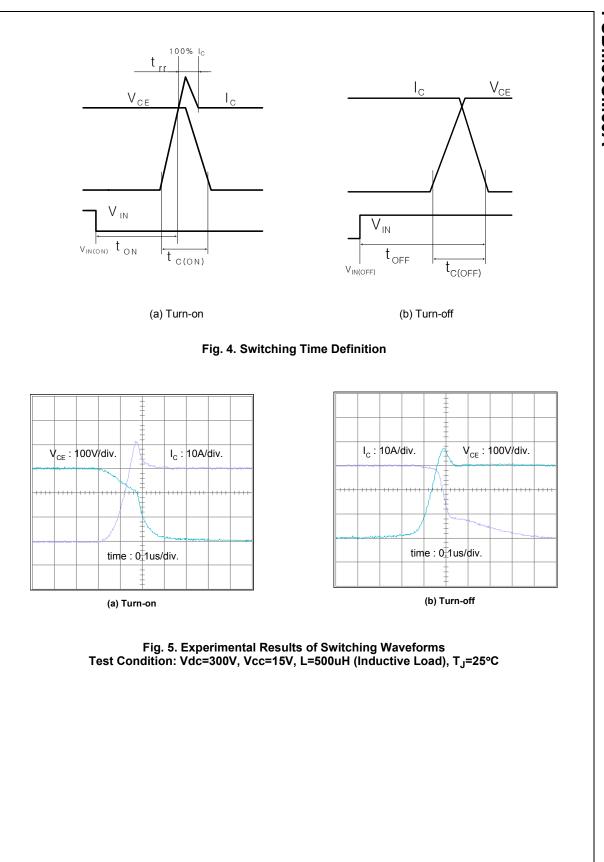
2. For the measurement point of case temperature( $T_C$ ), please refer to Fig. 2. 3. The thickness of thermal grease should not be more than 100um.

# Electrical Characteristics (T<sub>j</sub> = 25°C, Unless Otherwise Specified)

## **Inverter Part**

Item	Symbol	Conditio	on	Min.	Тур.	Max.	Unit
Collector - Emitter Saturation Voltage	V <sub>CE(SAT)</sub>	$V_{CC} = V_{BS} = 15V$ $V_{IN} = 0V$	I <sub>C</sub> = 30A, T <sub>J</sub> = 25°C	-	-	2.3	V
FWDi Forward Voltage	V <sub>FM</sub>	V <sub>IN</sub> = 5V	I <sub>C</sub> = 30A, T <sub>J</sub> = 25°C	-	-	2.6	V
Switching Times	t <sub>ON</sub>	V <sub>PN</sub> = 300V, V <sub>CC</sub> = V <sub>BS</sub> = 15V		-	0.39	-	us
	t <sub>C(ON)</sub>	I <sub>C</sub> = 30A, T <sub>J</sub> = 25°C		-	0.2	-	us
	t <sub>OFF</sub>	$V_{IN} = 5V \leftrightarrow 0V$ , Inductive Lo	ad	-	0.95	-	us
	t <sub>C(OFF)</sub>	(High, Low-side)		-	0.39	-	us
	t <sub>rr</sub>	(Note 4)		-	0.13	-	us
Collector - Emitter Leakage Current	I <sub>CES</sub>	$V_{CE} = V_{CES}, T_J = 25^{\circ}C$		-	-	250	μA

Note: 4. t<sub>ON</sub> and t<sub>OFF</sub> include the propagation delay time of the internal drive IC. t<sub>C(ON)</sub> and t<sub>C(OFF)</sub> are the switching time of IGBT itself under the given gate driving condition internally. For the detailed information, please see Fig. 4.



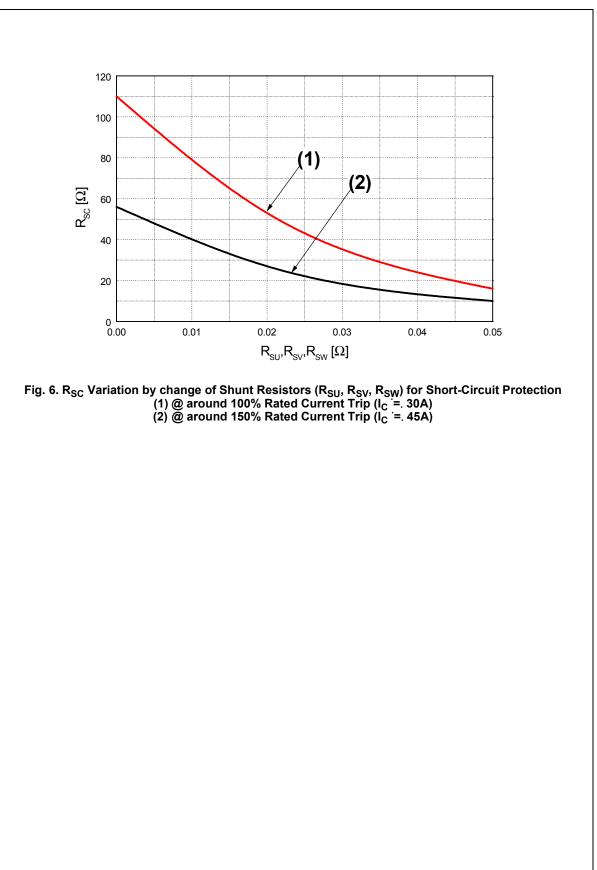
ltem	Symbol		Condition	Min.	Тур.	Max.	Unit
Quiescent $V_{CC}$ Supply Current	I <sub>QCCL</sub>	V <sub>CC</sub> = 15V IN <sub>(UL, VL, WL)</sub> = 5V	V <sub>CC(L)</sub> - COM <sub>(L)</sub>	-	-	26	mA
	I <sub>QCCH</sub>	V <sub>CC</sub> = 15V IN <sub>(UH, VH, WH)</sub> = 5V	$V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$	-	-	130	uA
Quiescent $\mathrm{V}_{\mathrm{BS}}$ Supply Current	I <sub>QBS</sub>	V <sub>BS</sub> = 15V IN <sub>(UH, VH, WH)</sub> = 5V	$ \begin{array}{l} V_{B(U)} \text{ - } V_{S(U)},  V_{B(V)} \text{ - } V_{S(V)}, \\ V_{B(W)} \text{ - } V_{S(W)} \end{array} $	-	-	420	uA
Fault Output Voltage	V <sub>FOH</sub>	V <sub>SC</sub> = 0V, V <sub>FO</sub> Circuit	:: 4.7kΩ to 5V Pull-up	4.5	-	-	V
	V <sub>FOL</sub>	V <sub>SC</sub> = 1V, V <sub>FO</sub> Circuit	: 4.7k $\Omega$ to 5V Pull-up	-	-	1.1	V
Short-Circuit Trip Level	V <sub>SC(ref)</sub>	V <sub>CC</sub> = 15V (Note 5)		0.45	0.51	0.56	V
Sensing Voltage of IGBT Current	V <sub>SEN</sub>	R <sub>SC</sub> = 56 Ω,  R <sub>SU</sub> = F (Note Fig. 6)	$R_{\rm SV}$ = $R_{\rm SW}$ = 0 $\Omega$ and $I_{\rm C}$ = 45A	0.45	0.51	0.56	V
Supply Circuit Under-	UV <sub>CCD</sub>	Detection Level		11.5	12	12.5	V
Voltage Protection	UV <sub>CCR</sub>	Reset Level		12	12.5	13	V
	UV <sub>BSD</sub>	Detection Level		7.3	9.0	10.8	V
	UV <sub>BSR</sub>	Reset Level		8.6	10.3	12	V
FaultOutput Pulse Width	t <sub>FOD</sub>	C <sub>FOD</sub> = 33nF (Note 6	)	1.4	1.8	2.0	ms
ON Threshold Voltage	V <sub>IN(ON)</sub>	High-Side	Applied between IN <sub>(UH)</sub> , IN <sub>(VH)</sub> ,	-	-	0.8	V
OFF Threshold Voltage	V <sub>IN(OFF)</sub>		IN <sub>(WH)</sub> - COM <sub>(H)</sub>	3.0	-	-	V
ON Threshold Voltage	V <sub>IN(ON)</sub>	Low-Side	Applied between IN <sub>(UL)</sub> , IN <sub>(VL)</sub> ,	-	-	0.8	V
OFF Threshold Voltage	V <sub>IN(OFF)</sub>	1	IN <sub>(WL)</sub> - COM <sub>(L)</sub>	3.0	-	-	V

Electrical Characteristics (T<sub>J</sub> = 25°C, Unless Otherwise Specified)

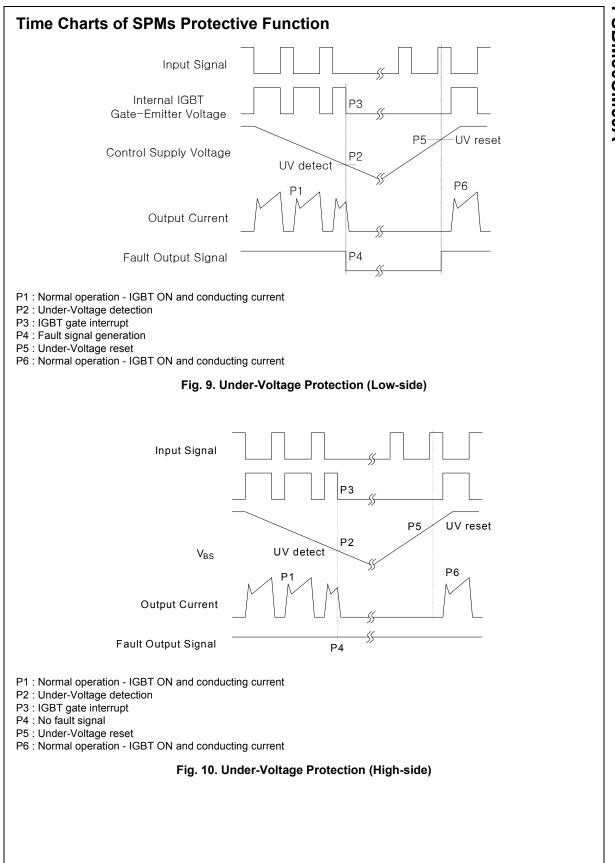
Note: 5. Short-circuit current protection is functioning only at the low-sides. It would be recommended that the value of the external sensing resistor ( $R_{SC}$ ) should be selected around 56  $\Omega$  in order to make the SC trip-level of about 45A at the shunt resistors ( $R_{SU}$ , $R_{SV}$ , $R_{SW}$ ) of  $\Omega\Omega$ . For the detailed information about the relationship between the external sensing resistor ( $R_{SC}$ ) and the shunt resistors ( $R_{SU}$ , $R_{SV}$ , $R_{SW}$ ), please see Fig. 6. 6. The fault-out pulse width  $t_{FOD}$  depends on the capacitance value of  $C_{FOD}$  according to the following approximate equation :  $C_{FOD}$  = 18.3 x 10<sup>-6</sup> x  $t_{FOD}[F]$ 

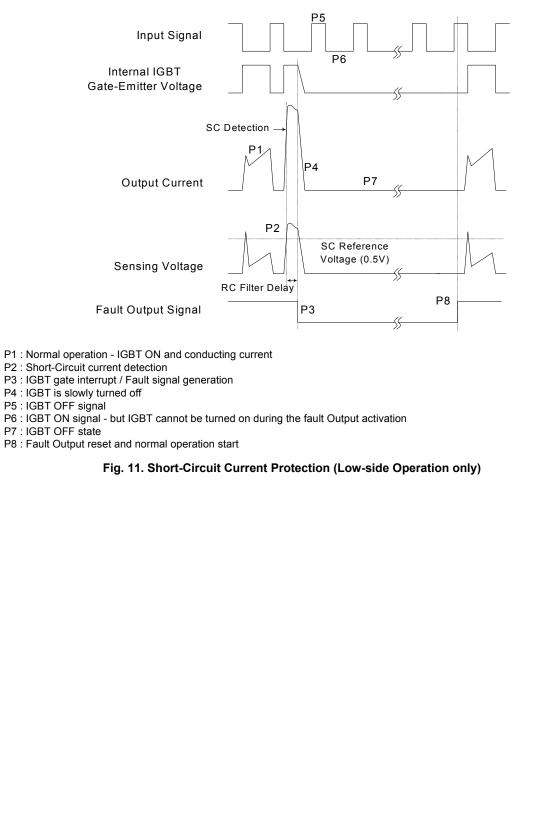
## **Recommended Operating Conditions**

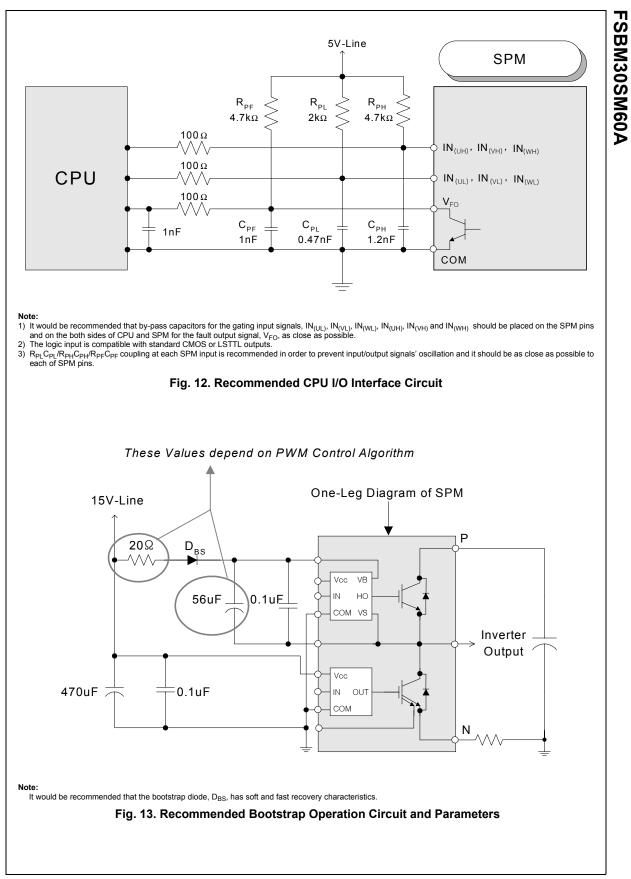
litere	Symbol Condition		Values			l lmit
ltem	Symbol	Ibol Condition		Тур.	Max.	Unit
Supply Voltage	V <sub>PN</sub>	Applied between P - N <sub>U</sub> , N <sub>V</sub> , N <sub>W</sub>	-	300	400	V
Control Supply Voltage	V <sub>CC</sub>	Applied between $V_{CC(UH)}$ , $V_{CC(VH)}$ , $V_{CC(WH)}$ - $COM_{(H)}$ , $V_{CC(L)}$ - $COM_{(L)}$	13.5	15	16.5	V
High-side Bias Voltage	V <sub>BS</sub>	Applied between $V_{B(U)}$ - $V_{S(U)}$ , $V_{B(V)}$ - $V_{S(V)}$ , $V_{B(W)}$ - $V_{S(W)}$	13.5	15	16.5	V
Blanking Time for Preventing Arm-short	t <sub>dead</sub>	For Each Input Signal	3	-	-	us
PWM Input Signal	f <sub>PWM</sub>	T <sub>C</sub> ≤ 100°C, T <sub>J</sub> ≤ 125°C	-	5	-	kHz
Input ON Threshold Voltage	V <sub>IN(ON)</sub>	$\begin{array}{l} \text{Applied between IN}_{(\text{UH})}, \text{IN}_{(\text{VH})}, \text{IN}_{(\text{WH})} - \\ \text{COM}_{(\text{H})}, \text{IN}_{(\text{UL})}, \text{IN}_{(\text{VL})}, \text{IN}_{(\text{WL})} - \text{COM}_{(\text{L})} \end{array}$	0 ~ 0.65		5	V
Input OFF Threshold Voltage	V <sub>IN(OFF)</sub>	$\begin{array}{l} \text{Applied between IN}_{(\text{UH})}, \text{IN}_{(\text{VH})}, \text{IN}_{(\text{WH})} \text{ -} \\ \text{COM}_{(\text{H})}, \text{IN}_{(\text{UL})}, \text{IN}_{(\text{VL})}, \text{IN}_{(\text{WL})} \text{ -} \text{COM}_{(\text{L})} \end{array}$		4 ~ 5.5		V



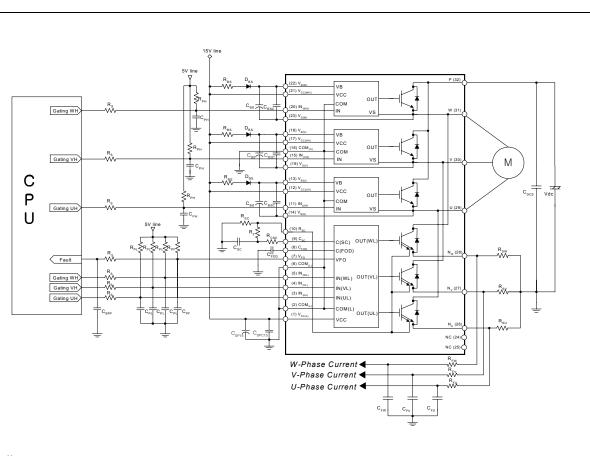
Item		Condition		Limits		Unit
			Min.	Тур.	Max.	Onit
Mounting Torque	Mounting Screw: M4	Recommended 10Kg•cm	8	10	12	Kg•cm
	(Note 7 and 8)	Recommended 0.98N•m	0.78	0.98	1.17	N•m
Ceramic Flatness		Note Fig.7	0	-	+120	um
Neight			-	35	-	g
		(+) TTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTTT	(+	)		
. Do not make over torque . Avoid one side tightenin	e or mounting screws. Much mounting	surement Position of The Ce ng torque may cause ceramic cracks and bol nded torque order for mounting screws. Unex	ts and AI heat-fir	n destruction.		c substrate
	e or mounting screws. Much mounting stress. Fig.8 shows the recommen	ng torque may cause ceramic cracks and bol	ts and AI heat-fir	n destruction.		c substrate
. Do not make over torque . Avoid one side tightenin	e or mounting screws. Much mounting stress. Fig.8 shows the recommen	ng torque may cause ceramic cracks and bol nded torque order for mounting screws. Unev	ts and AI heat-fir	n destruction.		c substrate







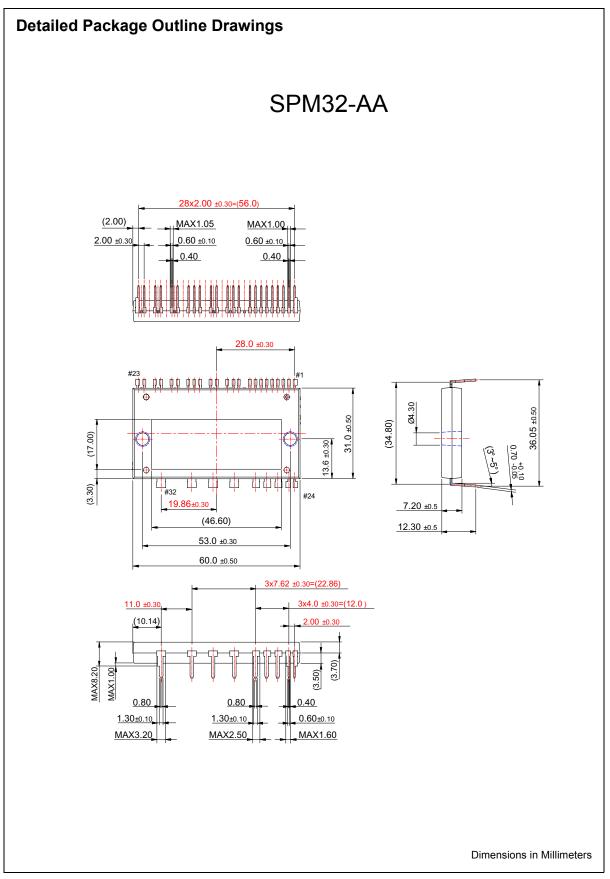
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### Note:

- R<sub>PL</sub>C<sub>PL</sub>/R<sub>PH</sub>C<sub>PH</sub>/R<sub>PF</sub>C<sub>PF</sub> coupling at each SPM input is recommended in order to prevent input signals' oscillation and it should be as close as possible to each SPM input pin.
- By virtue of integrating an application specific type HVIC inside the SPM, direct coupling to CPU terminals without any opto-coupler or transformer isolation is possible.
- V<sub>FO</sub> output is open collector type. This signal line should be pulled up to the positive side of the 5V power supply with approximately 4.7kΩ resistance. Please refer to Fig. 14.
- 4)  $C_{SP15}$  of around 7 times larger than bootstrap capacitor  $C_{BS}$  is recommended.
- 5)  $V_{FO}$  output pulse width should be determined by connecting an external capacitor(C<sub>FOD</sub>) between C<sub>FOD</sub>(pin8) and COM<sub>(L)</sub>(pin2). (Example : if C<sub>FOD</sub> = 33 nF, then  $t_{FO}$  = 1.8 ms (typ.)) Please refer to the note 6 for calculation method.
- 7) To prevent errors of the protection function, the wiring around  $R_{SC}$ ,  $R_F$  and  $C_{SC}$  should be as short as possible
- 8) In the short-circuit protection circuit, please select the R<sub>F</sub>C<sub>SC</sub> time constant in the range 3~4 μs.
   9) To enhance the noise immunity, C<sub>SC</sub> pin should be connected to the external circuit through a series resistor, R<sub>CSC</sub>, which is approximately 390Ω. R<sub>SCS</sub> should be connected to C<sub>SC</sub> pin as close as possible.
- 10)Each capacitor should be mounted as close to the pins of the SPM as possible.
- 11)To prevent surge destruction, the wiring between the smoothing capacitor and the P&N pins should be as short as possible. The use of a high frequency noninductive capacitor of around 0.1~0.22 uF between the P&N pins is recommended.
- 12)Relays are used at almost every systems of electrical equipments of home appliances. In these cases, there should be sufficient distance between the CPU and the relays. It is recommended that the distance be 5cm at least.

### Fig. 14. Typical Application Circuit



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CoolFET™	FRFET™	MicroPak™	QS™	TinyLogic®
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DOME™	GTO™	MSX™	Quiet Series <sup>™</sup>	TruTranslation™
EcoSPARK™	HiSeC™	MSXPro™	RapidConfigure™	UHC™
E <sup>2</sup> CMOS <sup>™</sup>	I²C™	OCX™	RapidConnect™	UltraFET <sup>®</sup>
EnSigna™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	VCX™
FACT™	ISOPLANAR™	OPTOLOGIC <sup>®</sup>	SMART START™	
Across the boar	d. Around the world.™	OPTOPLANAR™	SPM™	
The Power Fran		PACMAN™	Stealth™	
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### Definition of Terms

Datasheet Identification	Product Status	Definition
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Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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